Publikationen

Alexander Hofer, D. Liu, Günther Benstetter, M. Lanza, Werner Frammelsberger (2017): Chapter 3: Fundamentals of CAFM Operation Modes. In: Conductive Atomic Force Microscopy: Applications in Nanomaterials, Weinheim.

M. Brandt, Alexander Hofer, A. Greppmair, Tobias Berthold, Günther Benstetter (2016): Nanoscale electrical conductivity of laser-sintered Ge nanoparticle layers. In: The 8th International Conference On Technological Advances Of Thin Films and Surface Coatings (ThinFilms 2016), Singapur, Singapur.

M. Brandt, Alexander Hofer, A. Greppmair, Tobias Berthold, Günther Benstetter (2016): Nanoscale characterization of laser-sintered Ge nanoparticle layers. In: 2nd International Conference on Functional Integrated nano Systems (nanoFIS), Graz, Österreich.

Y. Ji, V. Igelsias, Alexander Hofer, M. Liu, D. Lewis, Y. Shi, S. Long, N. Jiebin, P. McIntyre, Günther Benstetter, A. Scheuermann, H. Fei, M. Lanza, Werner Frammelsberger (2016): Characterization of the photocurrents generated by the laser of atomic force microscopes. In: Review of Scientific Instruments, vol. 87, no. 8. DOI: 10.1063/1.4960597.

Alexander Hofer, K. Schiebl, Günther Benstetter (2015): Atomic Force Microscopy analysis of laser-sintered Germanium nanoparticles for thermoelectric applications. In: 3rd International Congress on Energy Efficiency and Energy Related Materials (ENEFM), Oludeniz, Türkei.

M. Brandt, Alexander Hofer, A. Greppmair, Günther Benstetter (2015): A review of physical characterization methods for nanostructured thermoelectric materials. Invited Talk. In: 3rd International Congress on Energy Efficiency and Energy Related Materials (ENEFM), Oludeniz, Türkei.

R.Y.Q. Fu, Alexander Hofer, Manuel Bogner, Günther Benstetter, H. Gruber (2015): Differential 3ω method for measuring thermal conductivity of AlN and SI3N4 thin films. In: Thin Solid Films, vol. 591 Part B, pp. 267-270. DOI: 10.1016/j.tsf.2015.03.031.

Alexander Hofer, M. Mattheis, L. Hamann, M. Haas, Günther Benstetter, R. Zapf-Gottwick (2015): Use of Coated-Metal Particles in Rear Busbar Pastes to Reduce Silver Consumption. In: IEEE Journal of Photovoltaics, vol. 5, no. 2, pp. 534-537. DOI: 10.1109/JPHOTOV.2014.2388080.

Alexander Hofer, Manuel Bogner, Günther Benstetter, H. Gruber (2014): The differential 3ω method for measuring the thermal conductivity of AlN and SI3N4 thin films. In: 16th International Conference on Thin Films (ICTF16), Dubrovnik, Kroatien.

Alexander Hofer, Tobias Berthold, Günther Benstetter (2014): Selected Atomic Force Microscopy Methods for the Electrical Characterization of Thin Films and Devices. Invited Talk. In: 4th International Advances in Applied Physics and Materials Science Congress & Exhibition (APMAS), Fethiye, Türkei.

Alexander Hofer, Günther Benstetter, R. Biberger, B. Wilke, H. Göbel (2013): Scanning probe microscopy based electrical characterization of thin dielectric and organic semiconductor films. In: 24th European Symposium on Reliability of Electron Devices, Failure Physics and Analysis (ESREF), Arcachon, Frankreich.

Alexander Hofer, Günther Benstetter, R. Biberger, B. Wilke, H. Göbel (2013): Scanning probe microscopy based electrical characterization of thin dielectric and organic semiconductor films. In: Microelectronics Reliability, vol. 53, no. 9-11, pp. 1430-1433.

Alexander Hofer, C. Leirer, Günther Benstetter, R. Biberger, G. Brüderl (2013): Analysis of crystal defects on GaN based semiconductors with advanced scanning probe microscope technique. In: Thin Solid Films, vol. 544, no. Oktober, pp. 139-143.

Alexander Hofer, C. Leirer, Günther Benstetter, R. Biberger, G. Brüderl (2012): Analysis of crystal defects on GaN-based semiconductors with advanced scanning probe microscope techniques. Invited Talk. In: 6th International Conference on Technological Advances of Thin Films & Surface Coatings (THINFILMS2012), Singapur, Singapur.

Alexander Hofer, Günther Benstetter, R. Biberger, B. Wilke, H. Göbel (2011): Capacitance and Conductivity Mapping of Organic Films and Devices with Non-Contact SPM Methods. In: International Workshop on Scanning Probe Microscopy for Energy Applications, Mainz.

Alexander Hofer, Günther Benstetter, R. Biberger, H. Göbel (2010): Intermittent-Contact Scanning Capacitance Analysis of Thin Dielectric Films and Semiconductor Devices. Invited Talk. In: 5th International Conference on Technological Advances of Thin Films & Surface Coatings, Harbin, China.

Edgar Lodermeier, Alexander Hofer, D. Liu, Heiko Ranzinger, Günther Benstetter, Peter Breitschopf, W. Bergbauer, Werner Frammelsberger (2006): Raster-Sonden-Mikroskopie (SPM) in der Fehler- und Zuverlässigkeitsanalytik. In: VDE Fehlermechanismen bei kleinen Geometrien, Grainau.

Edgar Lodermeier, Alexander Hofer, B. Knoll, Günther Benstetter, Peter Breitschopf, Werner Frammelsberger (2005): Intermittent Contact Scanning Capacitance Microscopy-First Results. In: Workshop on Scanning Probe Microscopy and Related Techniques, Villach, Österreich.